

# WaferSense® Auto Gapping System (AGS)

AGS

## ○ Improve Uniformity and Yield with the Wireless WaferSense AGS for Accurate and Repeatable Setups

Speeds non-contact gap measurements and parallelism adjustments under vacuum for semiconductor processes such as thin-film deposition, sputtering and etch.



### **Achieve the ideal set-up for your equipment by measuring gaps at three points.**

- Quickly achieve exactly the gap you need, using the chamber readings at process pressure in numerical and graphical form, with the easy-to-use GapView™ and GapReview™ software.
- Achieve the best uniformity, whether you need to set a gap that is perfectly parallel or slightly tilted.

### **Improve tool-to-tool process uniformity with objective and repeatable gap adjustments.**

- Have peace of mind by taking the human variable out of adjusting your equipment.
- Make the right adjustments time after time.
- Enable anyone to set the same gap across the tools.

### **Reduce equipment calibration time through live feedback.**

- See the effects of adjustments in real-time.
- Have a clear indication when equipment settings are within tolerance using measurements that can be taken from inside an evacuated process chamber.

### **Speed setups, maintenance and troubleshooting with automatic handling.**

- Save time and expense.

**Semiconductor fabs and OEMs worldwide value the accuracy, precision and versatility of the WaferSense AGS – The most efficient and effective wireless measurement device for chamber gapping.**

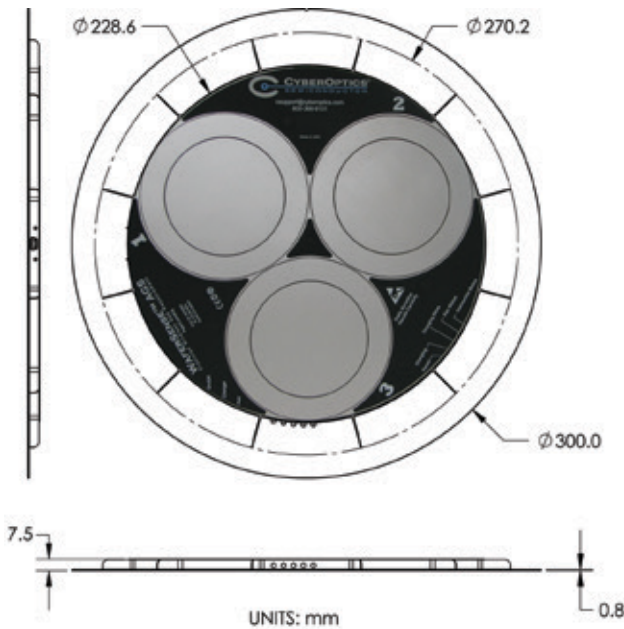


**Save Time. Save Expense. Improve Yields.**

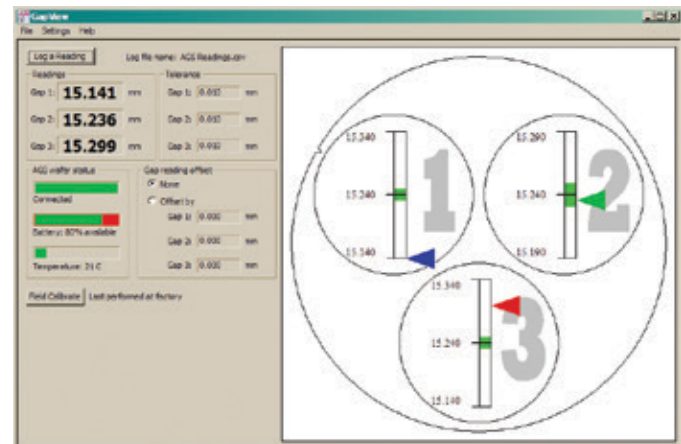
# Features

|   |  |
|---|--|
| <b>Wireless, wafer-shaped and battery-powered</b> | Available in 200mm, 300mm and 450mm  |
| <b>Easy-to-use software</b>                       | GapView and GapReview software included.<br>GapView: Displays real-time numerical and graphical data. Easily identify if it is above, below or within the target gap range.<br>GapReview: Replays log file data for review and analysis. |
| <b>Highly accurate</b>                            | Gap accuracy of +/-0.025 with gaps of 15mm within 4 hours of field calibration.<br><br>Resolution of 0.005mm   |
| <b>Durable housing</b>                            | Anodized aluminum (200 & 300mm), Carbon fiber composite (450mm)  |
| <b>Lightweight</b>                                | 225 grams (200mm), 400 grams (300mm), 750 grams (450mm)  |
| <b>Operating pressure</b>                         | <10e <sup>-6</sup> to 760 torr   |
| <b>Operating temperature</b>                      | 20 to 70 degrees C.  |
| <b>Battery-operation</b>                          | >4 hrs. per charge, 8 hrs. typical   |
| <b>WaferSense Link</b>                            | Bluetooth, 2.4 GHz, USB 1.1, dimensions 92mm x 58mm x 28mm   |
| <b>Operating Systems</b>                          | Windows 7, XP and Vista  |
| <b>Product components</b>                         | Gapping measurement device, charging clean case, carrying suitcase, USB communications link module and application software  |
| <b>Calibration</b>                                | Factory recalibration recommended annually   |
| <b>Options</b>                                    | AGS15 Fixture with a NIST traceable gap used to check/set AGS gap measurement accuracy.<br>AGS15L Field calibration fixture (for 450mm AGS).   |

## Dimensions (AGS300)



## GapView™



Real-time data.

Visit [www.cyberoptics.com](http://www.cyberoptics.com) for drawings of other form factors.



Contact CyberOptics today for your complimentary on-tool demonstration  
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